

Notice of References Cited

Application/Control No.

10/534,011

Applicant(s)/Patent Under
Reexamination
ZHAO ET AL.

Examiner

Andrew C. Lee

Art Unit

2419

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0046379	04-2002	Miki et al.	714/749
*	B	US-7,218,667	05-2007	Arima, Takenobu	375/148
*	C	US-6,385,437	05-2002	Park et al.	455/69
*	D	US-2002/0167907	11-2002	Sarkar et al.	370/252
*	E	US-6,615,382	09-2003	Kang et al.	714/748
*	F	US-7,120,134	10-2006	Tiedemann et al.	370/329
*	G	US-6,266,360	07-2001	Okamoto, Naoki	375/140
*	H	US-2002/0181437	12-2002	Ohkubo et al.	370/349
*	I	US-5,914,950	06-1999	Tiedemann et al.	370/348
*	J	US-2001/0019961	09-2001	Nakahara et al.	455/522
*	K	US-2004/0047305	03-2004	Ulupinar, Fatih	370/320
*	L	US-5,828,677	10-1998	Sayeed et al.	714/774
*	M	US-6,700,867	03-2004	Classon et al.	370/216

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.